Abstract

Epilepsy is a common brain disorder that affects one out of hundred patients. EEG
(electroencephalogram) is a signal that represents the effect of the superimposition of diverse processes in the brain. This paper investigates the possibility of Extreme Learning Machine (ELM) as a classifier for detecting and classifying the epilepsy of various risk levels from the EEG signals. The Singular Value Decomposition (SVD) is used for dimensionality reduction. Twenty patients are analysed in this study.

References

- Y. Song, P. Lio, "A new approach for epileptic seizure detection: sample entropy based feature extraction and extreme learning machine" in J. Biomedical Science and

Index Terms

Computer Science Applied Electrical Engineering

Keywords

Extreme Learning Machine Singular Value Decomposition Epilepsy Risk Level Seizure.